

Notice of References Cited	Application/Control No. 10/629,300	Applicant(s)/Patent Under Reexamination DEFEO ET AL.	
	Examiner Patricia L. Hailey	Art Unit 1755	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0028288	03-2002	Rohrbaugh et al.	427/180
*	B	US-5,824,145	10-1998	Marganski et al.	106/442
*	C	US-5,405,678	04-1995	Bilodeau, Wayne L.	428/32.1
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*	E	US-6,341,560	01-2002	Shah et al.	101/463.1
*	F	US-6,416,620	07-2002	Narancic et al.	162/5
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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